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## Communication

**Charge-Induced Second-Harmonic Generation in Bilayer WSe<sub>2</sub>**

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## Charge-Induced Second-Harmonic Generation in Bilayer WSe<sub>2</sub>

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**Controlling nonlinear light-matter interaction is important from fundamental science point of view as well as a basis for future optoelectronic devices<sup>1,2</sup>. Recent advances in two-dimensional crystals have created opportunities to manipulate nonlinear processes electrically<sup>3-8</sup>. Here we report a strong second-harmonic generation (SHG) in a 2D WSe<sub>2</sub> bilayer crystal caused by a back gate field. This unusual process takes place only when the gate polarity causes charge accumulation rather than depletion. Analysis based on bond-charge model traces the origin of SHG to the non-uniform field distribution within a single monolayer, caused by the accumulated sub-monolayer screening charge in the tungsten plane. We name this phenomenon charge-induced SHG (CHISHG), which is fundamentally different from the field- or current-induced SHG<sup>3-11</sup>. Our findings provide a potentially valuable technique for understanding and noninvasive probing of charge and current distributions in future low dimensional electronic devices.**

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3 Keywords: Charged-Induced Second-Harmonic generation, Two-Dimensional Layered Materials,  
4 Tungsten Diselenide, Bond Charge Model, Charge Accumulation, Screening Effect  
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11 2D atomic materials exhibit extraordinary optical and electronic properties and have been  
12 intensively investigated over the past decade or so<sup>12,13</sup>. With dimensions reduced to a monolayer,  
13 exceptional physical behaviors such as indirect-direct bandgap transition and inversion symmetry  
14 breaking have been discovered enabling various potential applications in nanoscale electronics  
15 and photonics<sup>14-17</sup>. Especially important is the ability to modulate the physical properties down to  
16 quantum size regime by external stimuli as it provides new avenues for exploring physics and  
17 technological applications. For instance, electric field and artificial stacking have been recently  
18 used for tuning orbital magnetic moment and Berry curvature of the Bloch states in bilayer  
19 graphene and two-dimensional transition metal dichalcogenides (TMDs)<sup>18-21</sup>.  
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31 In this work we demonstrate manipulation of the bond charges in a bilayer TMD by applying a  
32 perpendicular electric field, which causes significant modification of the nonlinear optical  
33 properties, manifested by second-harmonic generation (SHG). The key difference between our  
34 results and numerous prior works on electric-field-induced SHG (E-FISHG)<sup>3-6,9-11</sup>, is that  
35 CHISHG is observed only when the applied electric field causes space charge accumulation,  
36 which can occur in either accumulation or deep inversion mode of operation but not in the  
37 depletion mode. The microscopic origin of the effect can be traced to the specific nature of the  
38 electronic states at the direct band edges of 2D TMD<sup>22</sup> that are predominantly comprised of the  
39  $d_{xy}$  and  $d_{x^2-y^2}$  orbitals of transition metal (W) as shown in Fig. 1a and explained in greater detail  
40 in supplementary information. The accumulation charge is thus highly localized in the transition  
41 metal planes (*i.e.*,  $x$ - $y$  plane) and the DC field becomes highly non-uniform due to the screening  
42 effect, which is fundamentally different from E-FISHG in conventional metal-semiconductor or  
43 metal-oxide-semiconductor structures<sup>4,9-11</sup> where the effect has a macroscopic character. As a  
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3 result, E-FISHG, nearly forbidden by symmetry in case of uniform DC field, becomes allowed.  
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5 Thus SHG measurement can serve as a gauge of space charge and electric field distribution on a  
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7 sub-monolayer scale.  
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10 In our experiment, bilayer WSe<sub>2</sub> samples on 100-nm silicon oxide substrate were prepared by  
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12 mechanical exfoliation method confirmed by Raman spectroscopy which exhibits characteristic  
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14 low-frequency shear and breathing modes extremely sensitive to layer numbers in transitional  
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16 metal dichalcogenides<sup>23,24</sup>. The pristine WSe<sub>2</sub> layers stacked in 2H order have inversion symmetry,  
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18 leading to vanishing second-order optical nonlinearity (Fig. 1b)<sup>25-29</sup>. Back-gated field-effect  
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20 transistors (FETs) were fabricated using these flakes in order to investigate the charge-induced  
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22 SHG (see Methods). Source-drain electrodes remain grounded during the experiments (Fig. 1c)  
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24 for excluding the possibility of current-induced SHG<sup>7,8</sup>.  
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28 The results of gate-voltage-dependent SHG measurements are shown in Fig. 2a. At zero gate  
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30 bias ( $V_G = 0$  V), no SHG signal was detected. Upon the application of a negative gate bias  $V_G = -$   
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32 40 V, there is a charge (hole) accumulation in the sample and efficient SHG can be observed, as  
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34 shown by the back-gate sweep of source-drain current  $I_{sd}$  (Fig. 2b). The obtained transfer  
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36 characteristics are of typical *p*-type conduction operated in enhancement mode with a turn-on  
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38 threshold voltage  $V_T \sim -20$  V. In contrast, switching the polarity, *i.e.*,  $V_G = 40$  V yields no SHG  
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40 signal. In order to understand the evolution of SHG as a function of gate voltage we plotted the  
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42 magnitude of square root of SHG intensity (*i.e.*, relative change of charge-induced second-order  
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44 susceptibility  $\chi^{(2)}$ ) and superimposed it on  $I_{sd} - V_G$  characteristics as shown in Fig. 2b, which  
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46 represents the key result of this work. The charge-induced  $\chi^{(2)}$  is zero below threshold and  
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48 increases linearly after  $V_T$ , as the back gate voltage becomes increasingly negative indicating that  
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50  $\chi^{(2)}$  is proportional to the accumulated charge and thus justifying the term charge induced SHG  
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52 (CHISHG). Furthermore, we have performed power-dependent measurements which revealed a  
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54 quadratic dependence shown as log-log plot in Fig. 2c, a tell-tale sign of a second-order optical  
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3 process. The polarization symmetry of CHISHG was also investigated, as shown in Fig. 2d. The  
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5 observed six-fold symmetry, combined with further confirmation of the angle-independent  
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7 behavior of total amount of CHISHG, is identical to the one observed in the monolayer with  $D_{3H}$   
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9 symmetry<sup>28</sup>. The intensity of CHISHG signal from bilayer flake at  $V_G = -40$  V was about 1000  
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11 times less than SHG signal from a monolayer WSe<sub>2</sub> measured under the same experimental  
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13 conditions (Fig. 2e), indicating that  $\chi^{(2)}$  was about 30 times less. In order to demonstrate the  
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15 sufficient sensitivity of CW laser used here, we have successfully reproduced the asymmetric  
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17 threshold-like behavior in the hole-accumulation regime by using an femtosecond laser excitation  
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19 (as shown in supporting information Section 8).  
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24 To explicate these results a bond charge model<sup>30</sup> was invoked. In this model potential  
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26 difference between W and Se ions in each bond  $\hat{b}_n$  causes shift of the position of center of the  
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28 bond charge  $q_n$  relative to the bond center and gives rise to a second-order bond  
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30 hyperpolarizability  $\beta_n^{(2)}$ , responsible for the bulk susceptibility  $\chi^{(2)}$ <sup>1,2</sup>. When an in-plane optical  
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32 field  $E_\omega e^{i\omega t}$  is applied as shown in Fig. 3a (here we use  $y$  direction as an example), second-order  
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34 dipole moment  $p_{2\omega,n} = \beta_n^{(2)} (E_\omega \cdot \hat{b}_n)^2 e^{2i\omega t}$  is generated in each bond. Since the electric field  $E_\omega e^{i\omega t}$   
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36 makes different angles with each bond  $\hat{b}_n$ , the dipoles  $p_{2\omega,n}$  have different magnitudes and thus  
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38 cannot cancel, hence a non-vanishing monolayer polarization  $P_{2\omega} e^{2i\omega t}$  arises. In a more general  
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40 case, if the electric field  $E_\omega e^{i\omega t}$  is directed at an arbitrary angle  $\theta$  to one of the bonds, nonlinear  
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42 polarization has an angular dependence,  $P_{2\omega} \sim \cos(3\theta)$  considering the trigonal symmetry of the  
43  
44 bonds. That is what is observed in a monolayer of WSe<sub>2</sub>, but in a bilayer WSe<sub>2</sub>, the bonds in the  
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46 second monolayer have opposite symmetry in the  $x$ - $y$  plane with respect to the bonds in first layer.  
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48 As a result, nonlinear polarizations of two monolayers cancel and indeed no SHG has been  
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50 observed in a bilayer (see Fig. 1b).  
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3 When a gate field  $V_G$  is applied, it is natural to expect E-FISHG, yet this is not the case in TMD.  
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5 As shown in Fig. 3b, the perpendicular external electric field leads to upward shift bond charges  
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7  $q_n$  of all 6 bonds. However the hyperpolarizabilities  $\beta_{1-3}^{(2)}$  in the bottom half monolayer are  
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9 reduced as the bond charges in  $q_{1-3}$  move towards W ions reducing bond polarities, whereas for  
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11 the top half-monolayer bond charges in  $q_{4-6}$  move towards Se ions increasing  
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13 hyperpolarizabilities  $\beta_{4-6}^{(2)}$ . Therefore, on average neither polarity nor hyperpolarizability change,  
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15 and there is no change of overall  $\chi^{(2)}$ , which is in accordance with E-FISHG theory considering  
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17 that there is no third-order susceptibility tensor with out-of-plane element (e.g.,  $\chi_{xxx}^{(3)}$ ).  
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19 Consequently, no E-FISHG can be observed for as long as the applied DC field is uniform, which  
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21 is precisely what happens in the absence of accumulation charge.  
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27 When the gate voltage exceeds threshold, a hole accumulation layer is formed on the W  
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29  $5d_{x^2-y^2, xy}$  orbitals (Fig.1a) and it acts as a screening charge that prevents further field penetration  
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31 beyond this accumulation plane. Microscopically, reducing  $V_G$  beyond threshold compels bond  
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33 charge to shift further towards W atoms in the bottom half-mono-layer while not affecting the top  
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35 half-monolayer (Fig. 3c). This leads to a decrease in  $\beta_{1-3}^{(2)}$  which is no longer compensated and the  
36  
37 total  $\chi^{(2)}$  of the monolayer changes. For the bilayer described here the effect would have been  
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39 cancelled if a similar shielding charge  $Q_2$  had been accumulated in the second monolayer. But the  
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41 density of the band edge states is so high that practically the entire space charge is localized in the  
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43 W plane of the bottom layer as shown in Fig. 3d. As explained in supplementary information  
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45 (section 3), from simple electrostatic considerations the charge  $Q_2$  in the W plane of the top layer  
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47 is only 4% of the charge  $Q_1$ . Therefore, the field-induced change in  $\chi^{(2)}$  of the bottom monolayer  
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49 remains largely uncompensated resulting in non-vanishing overall  $\chi^{(2)}$ , proportional to  $|V_G - V_T|$ .  
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53 To summarize, it is the charge accumulation that induces SHG, which warrants using the term  
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55 “charge induced SHG – CHISHG” to describe the phenomenon observed in our experiments. The  
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SHG is possible only in the presence of accumulated charge, which can occur in either accumulation or inversion mode of operation, but not in the depletion mode. This observation is further confirmed by the results for the different WSe<sub>2</sub> sample with ambipolar transport characteristics, in which the CHISHG had been observed in the presence of both hole (accumulation mode) and electron (deep inversion mode) accumulation charges with no SHG observed between those two modes. (see Fig. S4).

To obtain an order-of-magnitude estimate of CHISHG and compare it with experimental results, we use the same simple bond charge model of  $\chi^{(2)}$ <sup>30</sup>. At  $V_G = -40$  V the effective gate-induced potential difference between the W and Se layers that causes shift of the bond charges and change of bond hyperpolarizability  $\Delta\beta^{(2)}(V)$  is given by  $\Delta V_{eff} = |V - V_T| t' / d_{ox} \approx 0.03$  V, where  $t' = 0.15$  nm is the distance between W and Se layers and  $d_{ox} = 100$  nm is the oxide thickness. This potential augments the existing effective potential difference between W and Se ions, usually referred to as heteropolar contribution to the bandgap  $C$ <sup>31-33</sup>. In a typical nonlinear material GaAs the heteropolar potential is  $C_{GaAs} = 4.3$  eV<sup>34</sup>. Second-order susceptibility is proportional to  $C$  of bonds, the cube of bond length  $l_B$  and the volume density of bonds  $N_B$ <sup>30</sup>. It follows that, since both theory and experimental data estimate the magnitudes of  $\chi^{(2)}$  of WSe<sub>2</sub> and GaAs are comparable<sup>35</sup>, we can estimate heteropolar potential for WSe<sub>2</sub> as  $C_{WSe_2} \approx C_{GaAs} (l_{B,GaAs} / l_{B,WSe_2})^3 (N_{B,GaAs} / N_{B,WSe_2}) \approx 0.83$  eV, a value that appears to be reasonable in view of lesser ionicity of WSe<sub>2</sub> (see supplementary information for details). We now relate the charge-induced susceptibility of a bilayer material  $\chi_{xxx,b}^{(2)}(V)$  to the susceptibility of one WSe<sub>2</sub> monolayer  $\chi_{xxx,m}^{(2)}(V)$  as  $\chi_{xxx,b}^{(2)}(V) / \chi_{xxx,m}^{(2)}(V) = \Delta\beta_b^{(2)}(V) / 2\beta_b^{(2)} \approx e\Delta V_{eff} / 2C_{WSe_2} \approx 0.02$  where factor of 1/2 takes into account the fact that only the bottom half-monolayer contributes to SHG in bilayer material. This result is quite close to our experimentally determined ratio of susceptibilities of 0.03 and thus confirms the validity of the model. Another possible contribution by direct charge



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3 accumulation *via* bond polarizability bleaching mechanism is weak and can be excluded (see  
4 supplementary information section 6). It is important to comment that the sharp threshold-like  
5 dependence of SHG can be explained only by the microscopic model developed here that takes  
6 into consideration underlying orbital structure but not by the conventional bulk  $\chi^{(2)}$  used in refs<sup>9-</sup>  
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11. This model also offers an explanation for the observed saturation (reduction in slope) of SHG intensity at large voltages (Fig. 2B). Since the energy difference between the direct ( $K$ ) and indirect ( $\Gamma$ ) band-edges (Fig.1A) is only about 100 meV (or less) eventually the accumulation charge spills-over into the  $\Gamma$  band-edge states, such that charge is no longer localized in a plane of W atoms but spread out between W and S atoms – hence the SHG efficiency growth is no longer proportional to the charge as is the case in Fig. 2b. It is also important to note that according to our model, CHISHG can occur only in direct bandgap TMDs having band extrema in the  $K$ -point of Brillouin zone and indeed when we have tested four-layer WSe<sub>2</sub> samples with an indirect bandgap no CHISHG had been observed.

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In summary, we have demonstrated a fundamentally new nonlinear optical phenomenon – CHISHG in TMDs and developed a microscopic physical model proving that SHG is engendered by the localized accumulation charge causing DC field nonuniformity. This CHISHG is fundamentally different from a recent work<sup>36</sup> on electric field control of the SHG in a monolayer of WSe<sub>2</sub> which was observed only at the exciton resonance and did not show threshold characteristics versus gate voltage. In contrast, in the bilayer of WSe<sub>2</sub> used in our experiments off-resonant (hence free from PL background) SHG has shown threshold and asymmetry behaviors that are unambiguously associated with the presence of mobile charges on the  $d$ -shells of W – a unique characteristic only to TMD materials. Our results demonstrate significance of charge and field distribution on the scale of a single atomic layer, and should serve as an impetus for potential applications in noninvasive probing of charge and current distributions in future low dimensional electronic devices.

## Methods

Bilayer WSe<sub>2</sub> flakes were exfoliated from commercial WSe<sub>2</sub> crystals using scotch-tape method on SiO<sub>2</sub>/Si substrates (100 nm SiO<sub>2</sub>). Bilayers were identified and confirmed using optical contrast in a microscope followed by atomic force microscopy and low-frequency Raman spectroscopy (see Fig. S1). Using electron beam lithography techniques back-gated field-effect transistors (FETs) were fabricated. Electrodes (5nm/50nm Ti/Pd) were then deposited on the patterned devices using UHV thermal evaporation followed by hot acetone lift-off. The device performance and gate dependent transport were then checked in a shielded Lakeshore probe station using an Agilent Parameter Analyzer B1500A. A linearly-polarized continuous-wave 1064-nm laser of 30 mW power was focused on the samples via a 100× objective (Leica, HCX PL FLUOTAR L 100×/0.75) and SHG signals were collected in the reflection geometry. A Short-pass filter (Semrock, FF01-770/SP-25) was used in front of the spectrometer. SHG signals were then dispersed by a grating of 600 g/mm and recorded by a liquid nitrogen cooled CCD. During the nonlinear optical measurements, a back gate voltage was applied while keeping source-drain electrodes grounded. The sensitivity of experiment was confirmed to be sufficient here by examining the quadratic power dependence of CHISHG. A linear polarizer was used to investigate the anisotropy of polarized SHG while rotating the bilayer samples. The observed six-fold symmetry indicated the capability of determining the crystal orientation of 2H-stacked bilayer WSe<sub>2</sub> crystals, which was only accessible in odd number layer samples<sup>25-29</sup>.

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**Supporting Information:** Additional information regarding device fabrication, characterization, polarization-dependent SHG intensity, bond-charge model analysis and CHISHG by a femtosecond laser can be found in Supporting Information online.

#### Author contributions

H.K.Y. and Q.X. conceived the idea; Q.X. and J.B.K. supervised the project; H.K.Y., D.T. and W.G.X. fabricated the devices and performed the experiments; H.K.Y., J.B.K., and Q.X. analyzed the data and co-wrote the manuscript. All the authors commented the manuscript.

#### Additional information

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#### Competing financial interests

The authors declare no competing financial interests.

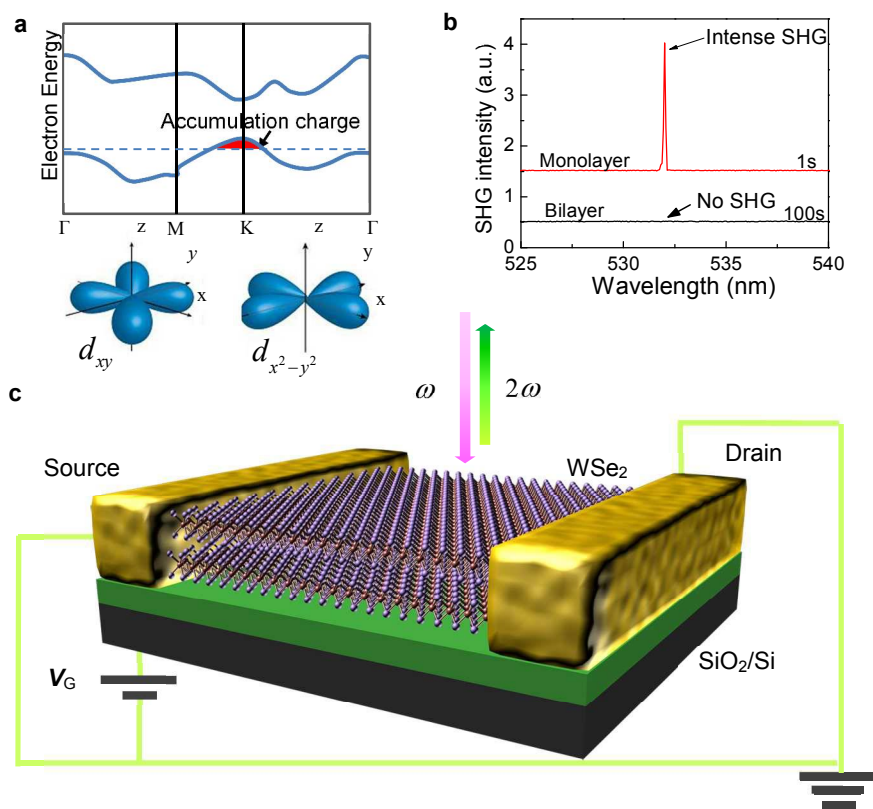
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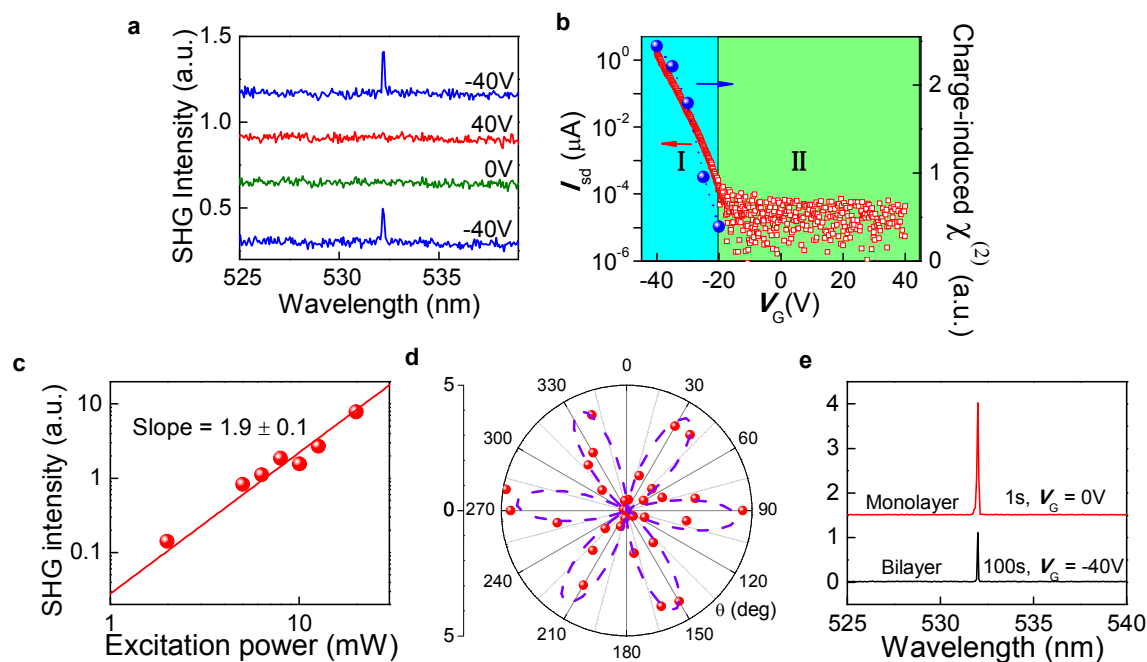
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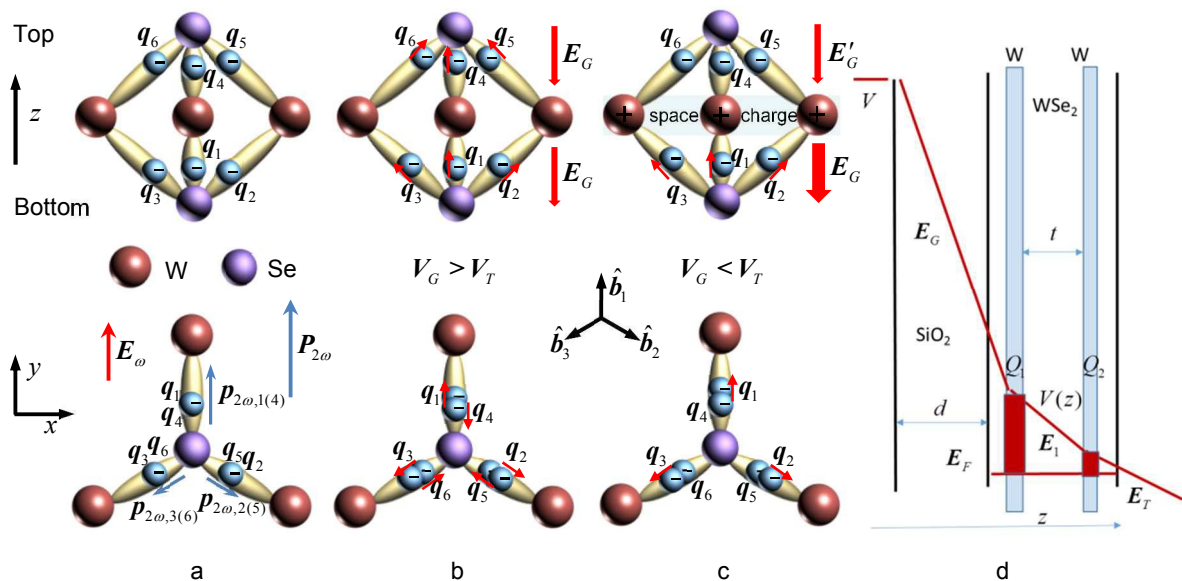
## Figures and Legends



**Figure 1 | SHG measurements of back-gated bilayer WSe<sub>2</sub> FET.** (a) Schematic energy diagram of monolayer WSe<sub>2</sub>. Holes are accumulated (red) under certain back-gate potentials. (b) Typical SHG spectra from monolayer and bilayer WSe<sub>2</sub> samples. The spectra have been shifted vertically for clarity. (c) Schematic diagram of the device configuration of WSe<sub>2</sub> during the SHG experiments.



**Figure 2 | Charge-induced SHG from bilayer WSe<sub>2</sub>.** (a) Reversible SHG induced by back gate can be seen from the pristine bilayer WSe<sub>2</sub> sample. The spectra have been shifted vertically for clarity. (b)  $I_{ds}$  vs.  $V_G$  curve of the bilayer WSe<sub>2</sub> device. The blue region ( I ) represents  $V_G < V_T$  (hole accumulation) while the green region ( II ) represents  $V_G > V_T$ . SHG intensities as function of gate voltage (blue dots) are superimposed on  $I_{ds}$  vs.  $V_G$  curve. (c) Log-log plot of power dependence of the CHISHG intensity on the incident laser power at  $V_G = -40$  V. The red circles represent the experimental data and the red line represents a linear fit with extracted slope  $1.9 \pm 0.1$ . (d) Polar plot of polarization-resolved CHISHG intensity (red circles) from the bilayer WSe<sub>2</sub> sample at  $V_G = -25$  V. The blue line shows the expected  $\cos^2(3\theta)$  dependence. (e) Red line shows the SHG intensity recorded from monolayer with detector integration time of 1 s and black line from bilayer at  $V_G = -40$  V with integration time of 100 s under the same experimental condition respectively. The charge-induced  $\chi_{xxx,b}^{(2)}(V)$  is estimated to be around 0.03 of  $\chi_{xxx,m}^{(2)}$ .



**Figure 3 | Bond-charge model upon back-gate fields.** (a) Schematic diagram of bond-charge distributions within one WSe<sub>2</sub> unit cell without external electric field, where  $q_n$  ( $n=1,2,3,4,5,6$ ) represents the bond charge of each W-Se bonds in one unit cell. Insets show the crystallographic axis and Cartesian coordinates. A total  $P_{2\omega}$  is generated while applying an in-plane optical field  $E_\omega$  polarized along the  $y$ -direction. (b) Perturbation of bond charges in each W-Se bonds while applying a DC gate field  $E_G$  (for  $V_G > V_T$ ) in the vertical direction, where the total second-order susceptibility remains unchanged and no E-FISHG is expected. (c) An atomically thin hole-charge sheet is generated while applying  $E_G$  (for  $V_G < V_T$ ), which pins the external electric field in the top half-monolayer. This screening effect is responsible for the observed CHISHG. (d) Schematic diagram of the electric field and charge distribution in the WSe<sub>2</sub>/SiO<sub>2</sub>/Si structure on application of a transverse field (not to scale). For  $V_G = -40$  V the electric field is pinned at the threshold field  $E_T$  for the top monolayer. The charges are non-uniformly distributed in the adjacent two monolayers due to screening.



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